Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/807,355	KARASAWA ET AL.	
Examiner	Art Unit	
Hien N. Nguyen	2824	

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Class	Subclass	Date	Examiner
365	145	7/20/2005	HN
365	149	7/20/2005	HN
			
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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DATE 7/20/2005	HN HN
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